Search Notes			

Application/Control No.	Applicant(s)/Patent under Reexamination	-
10/657,259	SHIRAISHI ET AL.	
Examiner	Art Unit	
Christopher S. Kim	3752	

	SEARCHED			
Class	Subclass	Date	Examiner	
239	533.12	7/7/2005	ск	

INT	INTERFERENCE SEARCHED		
Class	Subclass	Date	Examiner
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SEARCH (INCLUDING SEAR	NOTES RCH STRATEG	iY)
	DATE	EXMR